#### Digital Computer Laboratory Massachusetts Institute of Technology Cambridge, Massachusetts

## SUBJECT: HIGH-SPEED (5965) FLIP-FLOP

- To: Group 62 Engineers and Group 63 Engineers
- From: Hal Boyd
- Date: February 24, 1953
- Abstract: In this E-Note is presented a collection of data taken on the preliminary circuit of a high-speed, high-reliability, 5965 duo-triode flip-flop, that was designed to drive 7AK7 gate tubes. The procedure used in the design of this flip-flop is explained in E-525 entitled "The Normalized Flip-Flop Chart." A circuit schematic of the flip-flop, from which all data was taken, is shown in Figure 1, attached.

#### 1.0 P.R.F. Response Characteristics

The curves shown in Figure 2 were obtained by complementing the flip-flop with a continuous train of 0.1  $\mu$ sec pulses with various loads on both flip-flop outputs. The lower curves define the transition from the region of either inoperation or frequency division, to the region of absolute operation. The upper curve ( $\mu$ 5<sup>o</sup> line at 5 megacycles) defines the transition from the region of operation to the region in which both output levels coincide. In this latter region the flip-flop's memory is destroyed and the flip-flop assumes a third stable state in which counting is not reliable.

For 20-volt triggers with a range from 13 to 30 volts, the flip-flop can drive up to 100  $\mu\mu$ f/side (6-7, 7AK7 gate tubes per side) up to a maximum continuous p.r.f. of 4 megacycles.

#### 2.0 Counting Characteristics

Figure 3 was read directly from the output waveforms of the flip-flop while complementing at 1 Kc with 0.1  $\mu$ sec pulses. 15-volt and 25-volt negative triggers were used for complementing the flip-flop, and the output waveforms were observed with no load and with a load of 100  $\mu\mu$ f on each output of the flip-flop. Note that no additional delay would be necessary for use of the flip-flop in counting applications.

# 3.0 Variation of critical voltages with low I tubes

The worst combination of tube sides for the flip-flop tube is with one side of high L and the other of low L. The most critical voltages are the output levels, E and E, the flip-flop tube's cathode voltage,  $E_{\rm k}$ , the "on" tube's grid Voltage,  $E_{\rm gon}$ , and the "off" tube's grid voltage,  $E_{\rm k}$ . The manner in which these voltages vary as one tube side's  $L_{\rm b}$  varies is shown in Figure 4.

The L of the tube side in question was varied by its filament voltage. In the experiment, provision was made for switching the tube side from a tube testing circuit to the flip-flop circuit. Hence, at each filament voltage the L at 120 volts E and E = 0 was measured, and, at that same filament voltage, the behavior of the tube in the flip-flop was noted and the critical voltages were measured. The results were verified when, later, low  $I_b$  5965's were available.

#### 4.0 Supply Voltage Variations

Nominal Voltage	Limits	% Change	Output Levels
+150	+210	40%	+5 to -25
	0	100%	0 to -48
-150	-  > 300	100%	+.5 to -50
	-125	16.7%	+2.5 to -25
	-100	33.3%	+2.5 to -15

The above data is presented in terms of output voltage levels because failure of the flip-flop was arbitrarily taken as the point at which either output level falls within the range of from 0 to -25 volts; whereas flip-flop failure with respect to gate tubes defines a range of from 0 to -15 volts.

#### 5.0 Resistor and diode tolerances

Tolerances on resistors and diodes were taken one at a time, and the limits were defined by the point at which either output level falls within a range of from 0 to -25 volts. Figure 5 gives the maximum tolerance of each component, all others being held constant and within the tolerances shown on Figure 1.

## 6.0 Marginal Checking

Various components of the flip-flop were varied one at a time, and marginal checking voltages were determined for a number of values of

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each component. The marginal check voltage was inserted in the flip-flop at the spot marked "marginal check voltage" on Figure 1. The marginal checking voltage is centered, or has its base line, at -150 volts, and is taken to be the displacement from -150 volts. The manner in which the marginal checking voltage varies with percentage variations of each component is shown in Figures 6-12 inclusive. The solid curves indicate the picking up of a component on the same side of the flip-flop as the marginal checking voltage; whereas, the dotted curves are for components on the opposite side of the flip-flop.

Drawings:

SA-53718-1 SA-54002 SA-48396-G to 48405-G incl.

Signed

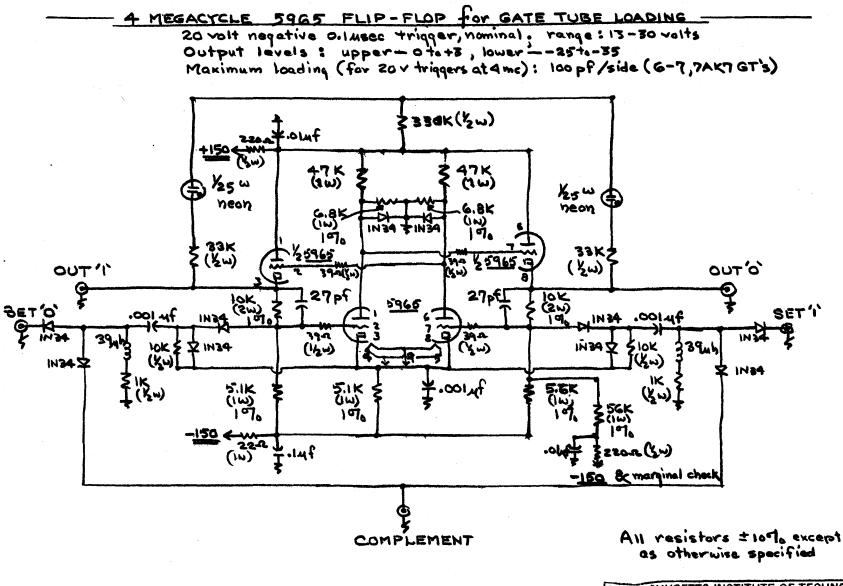
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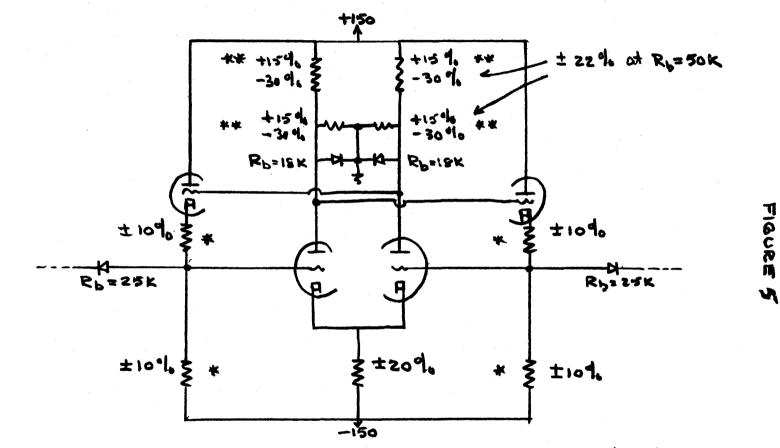
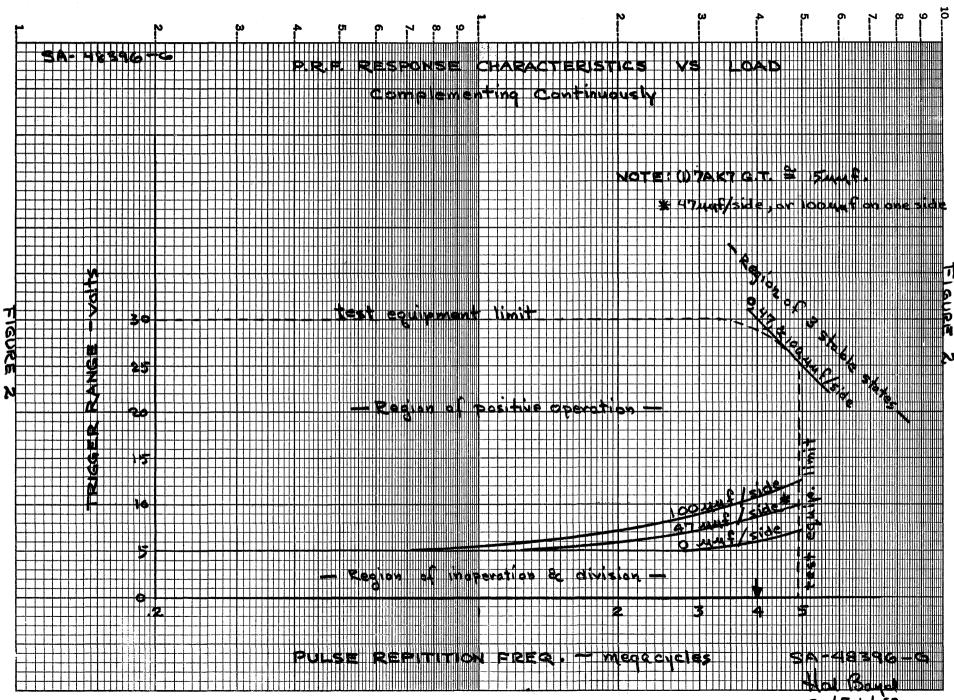


FIGURE 5

NOTES :

(x) If all four resistors vary in the worst directions, then each can vary 2.5 % before failure,

(\*\*) These limits (as are all others) are defined by output levels of 0 to +3, and/or -25 to -35 velts. If -40 velts were taken as one of the limits instead of -35, then the +1590 tolerance would be increased to +6090. Also, as the plate-circuit-diode's back resistance decreases, the upper limit increases and the lower, limit decreases. SA-54002 20 Feb #3



<sup>20/</sup> F=6/33

